

Rev D2, Page 1/29

FEATURES **APPLICATIONS** PGA inputs to 500 kHz for differential and single-ended sensor Programmable sensor interface signals for optical and magnetic position sensors Selectable adaptation to voltage or current signals Linear gauges and incremental Flexible pin assignment due to signal path multiplexers encoders Sine/Cosine signal conditioning for offset, amplitude and Linear scales phase Separate index signal conditioning Short-circuit-proof and reverse polarity tolerant output drivers $(1 \text{ Vpp to } 100 \Omega)$ Stabilized output signal levels due to sensor control Signal and system monitoring with configurable alarm output PACKAGES Supply voltage monitoring with integrated switches for reversed-polarity-safe systems Excessive temperature protection with sensor calibration I²C multimaster interface Supply from 4.3 to 5 V, operation within -25(-40) to +100 °C THURSDAY Suitable for SAFETY applications TSSOP20, TSSOP20-TP Verifyable chip release code Version iC-MSB2 with output multiplexer (not for SAFETY)





Rev D2, Page 2/29

DESCRIPTION

iC-MSB is a signal conditioner with line drivers for sine/cosine sensors which are used to determine positions in linear and angular encoders, for example.

Programmable instrumentation amplifiers with selectable gain levels permit differential or referenced input signals; at the same time the modes of operation differentiate between high and low input impedance. This adaptation of the iC to voltage or current signals enables MR sensor bridges or photosensors to be directly connected up to the device.

The integrated signal conditioning unit allows signal amplitudes and offset voltages to be calibrated accurately and also any phase error between the sine and cosine signals to be corrected. Separate zero signal conditioning settings can be made for the gain and offset; data is then output either as an analog or a differential square-wave signal (low/high level analogous to the sine/cosine amplitude).

For the stabilization of the sine and cosine output signal levels a control signal is generated from the conditioned and calibrated input signals which can power the transmitting LED of optical systems via the integrated 50 mA driver stage (output ACO). If MR sensors are connected this driver stage also powers the measuring bridges.

By tracking the sensor energy supply any signal variations and temperature and aging effects can be compensated for and the set signal amplitude maintained with absolute accuracy. At the same time the control circuitry monitors both whether the sensor is functioning correctly and whether it is properly connected; signal loss due to wire breakage, short circuiting, dirt or aging, for example, is recognized when control thresholds are reached and indicated at alarm output ERR.

iC-MSB is protected against a reversed power supply voltage; the integrated voltage switch for loads of up to 20 mA extends this protection to cover the overall system. The analog output drivers are directly cablecompatible and tolerant to false wiring; if supply voltage is connected up to these pins, the device is not destroyed.

The device configuration and calibration parameters are CRC protected and stored in an external EEP-ROM; they are loaded automatically via the I2C interface once the supply voltage has been connected up.

A safety-technical analysis of iC-MSB on device level with the inclusion of layout and internal/external circuitry has been carried out together with the BGIA, St. Augustin. The result proved iC-MSB's capability for safety oriented applications with Siemens Sinumerik Controls.



Rev D2, Page 3/29

CONTENTS

| PACKAGES | 4 |
|--|-----------------------------|
| ABSOLUTE MAXIMUM RATINGS | 5 |
| THERMAL DATA | 5 |
| ELECTRICAL CHARACTERISTICS | 6 |
| PROGRAMMING | 10 |
| SERIAL CONFIGURATION INTERFACE (EEPROM) Example of CRC Calculation Routine EEPROM Selection | 13 13 13 14 |
| BIAS SOURCE AND TEMPERATURE SENSOR CALIBRATION | 15 |
| OPERATING MODES | 16 |
| Calibration Op. Modes | 16 |
| Special Device Test Functions | 16 |
| Signal Filter | 16 |
| TEST MODE | 17 |
| INPUT CONFIGURATIONS | 18 |
| Input Configurations | 18 |

| SIGNAL PATH MULTIPLEXING: iC-MSB ^{SAFETY} | 18 |
|---|----|
| EXTENDED SIGNAL PATH MULTIPLEXING: iC-MSB2 (not for safety applications) | 19 |
| SIGNAL CONDITIONING CH1, CH2 | 21 |
| Gain Settings CH1, CH2 | 21 |
| Offset Calibration CH1, CH2 | 22 |
| Phase Correction CH1 vs. CH2 | 22 |
| SIGNAL CONDITIONING CH0 | 23 |
| Gain Settings CH0 | 23 |
| Offset Calibration CH0 | 23 |
| SIGNAL LEVEL CONTROL and SIGNAL MONITORING | 24 |
| ERROR MONITORING AND ALARM OUTPUT | 25 |
| Error Protocol | 25 |
| I/O pin ERR | 25 |
| TEMPERATURE MONITORING | 26 |
| REVERSE POLARITY PROTECTION | 26 |
| APPLICATION HINTS | 27 |
| Connecting MR sensor bridges for | ~- |
| satety-related applications | 27 |
| PLC Operation | 27 |



Rev D2, Page 4/29

PACKAGES

PIN CONFIGURATION TSSOP20, TSSOP20-TP



PIN FUNCTIONS

No. Name Function

- 1 X1 Signal Input 1 (Index +)
- 2 X2 Signal Input 2 (Index -)
- 3 X3 Signal Input 3
- 4 X4 Signal Inout 4
- 5 VDDS Switched Supply Output (reverse polarity proof, load to 20 mA max.)
- 6 GNDS Switched Ground (reverse polarity proof)
- 7 X5 Signal Input 5
- 8 X6 Signal Input 6
- 9 ACO Signal Level Controller, high-side current source output
- 10 SDA Serial Configuration Interface, data line
- 11 SCL Serial Configuration Interface, clock line
- 12 NC Neg. Cosine Output
- 13 PC Pos. Cosine Output
- 14 NS Neg. Sine Output
- 15 PS Pos. Sine Output
- 16 GND Ground
- 17 VDD +4.5 to +5.5 V Supply Voltage
- 18 NZ Neg. Index Output
- 19 PZ Pos. Index Output
- 20 ERR Error Signal (In/Out), Test Mode Trigger Input

To improve heat dissipation the *thermal pad* of the TSSOP20-TP package (bottom side) should be joined to an extended copper area which must have GNDS potential.



Rev D2, Page 5/29

ABSOLUTE MAXIMUM RATINGS

These ratings do not imply operating conditions; functional operation is not guaranteed. Beyond these ratings device damage may occur.

| ltem | Symbol | Parameter | Conditions | | | Unit |
|------|--------|---|--|------|---------------|----------|
| No. | - | | | Min. | Max. | |
| G001 | V() | Voltage at VDD, GND, PC, NC, PS, NS, PZ, NZ, ACO | | -6 | 6 | V |
| G002 | V() | Voltage at ERR | | -6 | 8 | V |
| G003 | V() | Pin-To-Pin Voltage between VDD, GND, PC, NC, PS, NS, PZ, NZ, ACO, ERR | | | 6 | V |
| G004 | V() | Voltage at X1X6, SCL, SDA | | -0.3 | VDDS + 0.3 | V |
| G005 | I(VDD) | Current in VDD | | -100 | 100 | mA |
| G006 | I() | Current in VDDS, GNDS | | -50 | 50 | mA |
| G007 | I() | Current in X1X6, SCL, SDA, ERR, PC, NC, PS, NS, PZ, NZ | | -20 | 20 | mA |
| G008 | I(ACO) | Current in ACO | | -100 | 20 | mA |
| G009 | Vd() | ESD Susceptibility at all pins | HBM 100 pF discharged through 1.5 k Ω | | 2 | kV |
| G010 | Ptot | Permissible Power Dissipation | TSSOP20 TSSOP20-TP | | 300 400 | mW mW |
| G011 | Tj | Junction Temperature | | -40 | 150 | °C |
| G012 | Ts | Storage Temperature Range | | -40 | 150 | °C |

THERMAL DATA

| ltem | Symbol | Parameter | Conditions | | | | Unit |
|------|--------|-------------------------------------|---|------------|------|------------|-------|
| No. | | | | Min. | Тур. | Max. | |
| T01 | Та | Operating Ambient Temperature Range | iC-MSB TSSOP20, iC-MSB2 TSSOP20 iC-MSB TSSOP20-TP | -25 -40 | | 100 115 | ဂံ ပံ |
| T02 | Rthja | Thermal Resistance Chip to Ambient | TSSOP20 surface mounted to PCB according to JEDEC 51 | | 80 | | K/W |
| T03 | Rthja | Thermal Resistance Chip to Ambient | TSSOP20-TP surface mounted to PCB according to JEDEC 51 | | 35 | | K/W |



Rev D2, Page 6/29

| ltom | Symbol | Parameter | Conditions | T | | | Unit |
|-------|--------------|--|---|----------|-----------|-------|----------|
| No. | Symbol | Farameter | Conditions | Min. | Typ. | Max. | Unit |
| Total | Device | | 1 | | , ,, | | 1 |
| 001 | VDD | Permissible Supply Voltage | Load current I(VDDS) < -10 mA | 4.3 | | 5.5 | V |
| | | | | 4.5 | | 5.5 | V |
| 002 | I(VDD) | Supply Current in VDD | Tj = 27 °C, no load | | 25 | 50 | mA |
| 003 | I(VDDS) | Permissible Load Current VDDS | | -20 | | 0 | mA |
| 004 | Vcz()hi | Clamp Voltage hi at all pins | | | | 11 | V |
| 005 | Vc()hi | Clamp Voltage hi at inputs SCL, SDA | Vc()hi = V() - V(VDDS), I() = 1 mA | 0.4 | | 1.5 | V |
| 006 | Vc()hi | Clamp Voltage hi at inputs X1X6 | Vc()hi = V() - V(VDDS), I() = 4 mA | 0.3 | | 1.2 | V |
| 007 | Vc()lo | Clamp Voltage lo at all pins | I() = -4 mA | -1.2 | | -0.3 | V |
| Signa | l Conditioni | ing, Inputs X3X6 | | | | | |
| 101 | Vin()sig | Permissible Input Voltage Range | RIN12(3:0) = 0x01 | 0.75 | | VDDS | V |
| | | | DIN(12/2:0) 0::00 | 0 | | - 1.5 | V |
| 100 | lin()oig | Dermissible legut Current Denge | RIN12(3:0) = 0.009 | 0 | + | VDDS | V |
| 102 | lin()sig | Permissible input Current Range | RIN12(0) = 0, BIAS12 = 0 RIN12(0) = 0, BIAS12 = 1 | -300 | | 300 | μΑ |
| 103 | lin() | Input Current | RIN12(3:0) = 0x01 | -10 | + | 10 | μA |
| 104 | Rin() | Input Resistance vs. VREFin | $T_{i} = 27 ^{\circ}C^{\circ}$ | | + | | |
| | | | RIN12(3:0) = 0x09 | 16 | 20 | 24 | kΩ |
| | | | RIN12(3:0) = 0x00 | 1.1 | 1.6 | 2.1 | kΩ |
| | | | RIN12(3:0) = 0x02 | 1.6 | 2.3 | 3.0 | kΩ |
| | | | RIN12(3:0) = 0x04 RIN12(3:0) = 0x06 | 2.2 | 3.2 | 4.2 | kΩ kΩ |
| 105 | | Temperature Coefficient Rin | 1(1(12(3.0) = 0,00 | 5.2 | 0.15 | 0.0 | %/K |
| 105 | VREFin12 | Reference Voltage | BIN12(0) = 0 $BIAS12 = 1$ | 1 35 | 1.5 | 1.65 | 70/TX |
| 100 | | | RIN12(0)=0, BIAS12=1 RIN12(0)=0, BIAS12=0 | 2.25 | 2.5 | 2.75 | V |
| 107 | G12 | Selectable Gain Factors | RIN12(3:0) = 0x01, $GR12$ and $GF12 = 0x0RIN12(3:0) = 0x01$, $GR12$ and $GF12 = max$. | | 100 | | |
| | | | RIN12(3:0) = 0x09, GR12 and GF12 = 0x0 RIN12(3:0) = 0x09, GR12 and GF12 = max. | | 0.5 25 | | |
| 108 | ⊿Gdiff | Differential Gain Accuracy | calibration range 11 bit | -0.5 | | 0.5 | LSB |
| 109 | ⊿Gabs | Absolute Gain Accuracy | calibration range 11 bit, guaranteed monotony | -1 | | 1 | LSB |
| 110 | Vin()diff | Recommended Differential Input | Vin()diff = V(CHPx) - V(CHNx), | 10 | | 500 | m\/nn |
| | | voltage | RUIN12(3) = 0 | 40 | | 2000 | mVpp |
| 111 | Vin()os | Input Offset Voltage | refered to side of input | 0 | 20 | | μV |
| 112 | VOScal | Offset Calibration Range | referenced to the selected source (VOS12): | | 1 | | |
| | | j | ORx = 00 | | ±100 | | %V() |
| | | | ORx = 01 | | ±200 | | %V() |
| | | | ORx = 10 | | ±600 | | %V() |
| | | | URx = 11 | <u> </u> | ±1200 | | %V() |
| 113 | ⊿VOSdiff | Offset Correction | calibration range 11 bit | -0.5 | | 0.5 | LSB |
| 114 | ∆VOSint | Integral Linearity Error of Offset Correction | calibration range 11 bit | -1 | | 1 | LSB |
| 115 | PHIkorr | Phase Error Calibration Range | CH1 versus CH2 | | ±10.4 | | • |
| 116 | ⊿PHIdiff | Differential Linearity Error of Phase Calibration | calibration range 10 bit | -0.5 | | 0.5 | LSB |
| 117 | ⊿PHlint | Integral Linearity Error of Phase Calibration | calibration range 10 bit | -1 | | 1 | LSB |
| 119 | fin()max | Permissible Input Frequency | | 500 | 1 | | kHz |
| 120 | fhc() | Input Amplifier Cut-off Frequency (-3dB) | | 250 | | | kHz |



Rev D2, Page 7/29

| Competence of the second secon | | | | | | | | |
|--|-------------|--|---|--------------------------------|--------------------------------|--------------------------------|------------------------------|--|
| ltem No. | Symbol | Parameter | Conditions | Min. | Тур. | Max. | Unit | |
| Signal | Conditioni | ing, Inputs X1, X2 | | | | | | |
| 201 | Vin()sig | Permissible Input Voltage Range | RIN0(3:0) = 0x01 | 0.75 | | VDDS - 1.5 | V | |
| | | | RIN0(3:0) = 0x09 | 0 | | VDDS | V | |
| 202 | lin()sig | Permissible Input Current Range | RIN0(0) = 0, BIAS0 = 0 RIN0(0) = 0, BIAS0 = 1 | -300 10 | | -10 300 | μA μA | |
| 203 | lin() | Input Current | RIN0(3:0) = 0x01 | -10 | | 10 | uA | |
| 204 | Vout(X2) | Output Voltage at X2 | BIASEX = 10, $I(X2) = 0$, referenced to VREFin12 | 95 | 100 | 105 | - ⁻ | |
| 205 | Vin(X2) | Permissible Input Voltage at X2 | BIASEX=11 | 0.5 | | VDDS - 2 | V | |
| 206 | Rin(X2) | Input Resistance at X2 | BIASEX = 11, RIN0(3:0) = 0x01, RIN12(3:0) = 0x01 | 20 | 27 | 30 | kΩ | |
| 207 | Rin() | Input Resistance vs. VREFin | Tj = 27 °C; RIN0(3:0) = 0x09 RIN0(3:0) = 0x00 RIN0(3:0) = 0x02 RIN0(3:0) = 0x04 RIN0(3:0) = 0x06 | 16 1.1 1.6 2.2 3.2 | 20 1.6 2.3 3.2 4.6 | 24 2.1 3.0 4.2 6.0 | kΩ kΩ kΩ kΩ kΩ | |
| 208 | TCRin() | Temperature Coefficient Rin | | | 0.15 | | %/K | |
| 209 | VREFin0 | Reference Voltage | RIN0(0) = 0, BIAS0 = 1 RIN0(0) = 0, BIAS0 = 0 | 1.35 2.25 | 1.5 2.5 | 1.65 2.75 | V V | |
| 210 | G0 | Selectable Gain Factors | RIN0(3:0) = 0x01, GR0 and GF0 = 0x0 RIN0(3:0) = 0x01, GR0 and GF0 = max. | | 2 100 | | | |
| | | | RIN0(3:0) = 0x09, GR0 and GF0 = 0x0 RIN0(3:0) = 0x09, GR0 and GF0 = max | | 0.5 25 | | | |
| 211 | ⊿Gdiff | Differential Gain Accuracy | calibration range 5 bit | -0.5 | | 0.5 | LSB | |
| 212 | ⊿Gabs | Absolute Gain Accuracy | calibration range 5 bit, guaranteed monotony | -1 | | 1 | LSB | |
| 213 | Vin()diff | Recommended Differential Input Voltage | Vin()diff = V(CHP0) - V(CHN0), RIN0(3:0) = 0x01 RIN0(3:0) = 0x09 | 10 40 | | 500 2000 | mVpp mVpp | |
| 214 | Vin()os | Input Offset Voltage | referred to side of input | 0 | 75 | | μV | |
| 215 | VOScal | Offset Calibration Range | referenced to the selected source (REFVOS); OR0 = 00 OR0 = 01 OR0 = 10 OR0 = 11 | | ±100 ±200 ±600 ±1200 | | %V() %V() %V() %V() | |
| 216 | ∆VOSdiff | Differential Linearity Error of Offset Correction | calibration range 6 bit | -0.5 | | 0.5 | LSB | |
| 217 | ∆VOSint | Integral Linearity Error of Offset Correction | calibration range 6 bit | -1 | | 1 | LSB | |
| Signa | Filter | | | | | | | |
| 301 | fg | Cut-off Frequency | | | | 4000 | kHz | |
| 302 | phi | Phase Shift | fin 500 kHz for sine/cosine | | | 10 | 0 | |
| Index | Pulse Com | parator Output PZ, NZ | и | | | | <u>u</u> | |
| 401 | Vpk() | Output Amplitude With Sensor Tracking via ACO | EAZ = 1, ADJ(4:0) = 0x19 | 225 | 250 | 275 | mV | |
| 402 | SR() | Output Slew Rate | EAZ=1 | | 1 | | V/µs | |
| Line D | river Outpu | uts PS, NS, PC, NC, PZ, NZ | | | | | | |
| 501 | Vpk()max | Permissible Output Amplitude | VDD = 4.5 V, DC level = VDD / 2, RL = 50 Ω vs. VDD / 2 | | | 300 | mV | |
| 502 | Vpk() | Output Amplitude With Sensor Tracking via ACO | ADJ (8:0) = 0x19 | 225 | 250 | 275 | mV | |
| 503 | fg | Cut-off Frequency | CL = 250 pF | 500 | 1 | | kHz | |
| 504 | Vos | Offset Voltage | · · · | | ±200 | | μV | |
| 505 | lsc() | Short-circuit Current | pin shorten to VDD or GND | 10 | 30 | 50 | mA | |
| 506 | llk() | Tristate Leakage Current | tristate or reversed supply | -1 | 1 | 1 | μA | |



Rev D2, Page 8/29

| Item | Symbol | Parameter | Conditions | 1 | | | Unit |
|--------|-------------|--|---|-------|------|-------|----------|
| No. | Cymbol | | Conditions | Min. | Тур. | Max. | Onic |
| Signa | Level Cor | ntroller ACO | | | | 1 | 11 |
| 601 | Vs()hi | Saturation Voltage hi | Vs() = VDD - V(); | | | | |
| | 0 | at ACO vs. VDD | ADJ(8:0) = 0x11F, I() = -5 mA | | | 1 | V |
| | | | ADJ(8:0) = 0x13F, I() = -10 mA | | | | |
| | | | ADJ(8:0) = 0x15F, I() = -25 MA ADJ(8:0) = 0x17F I() = -50 mA | | | 1 | |
| 602 | lsc()bi | Short-circuit Current bi in ACO | V() = 0 $V(D = 1)/2$ | | | - | |
| 002 | 130()111 | | ADJ(8:0) = 0x11F | -10 | | -5 | mA |
| | | | ADJ(8:0) = 0x13F | -20 | | -10 | mA |
| | | | ADJ(8:0) = 0x15F | -50 | | -25 | mA |
| | | | ADJ(8:0) = 0x17F | -100 | | -50 | mA |
| 603 | tr() | Current Rise Time in ACO | I(ACO): $0 \rightarrow 90\%$ setpoint | | 1 | | ms |
| 604 | tset() | Current Settling Time in ACO | Square control active, I(ACO): $50 \rightarrow 100 \%$ setpoint | | 400 | | μs |
| 605 | lt()min | Control Range Monitoring 1: lower limit | referenced to range ADJ(6:5) | | 3 | | %lsc |
| 606 | lt()max | Control Range Monitoring 2: upper limit | referenced to range ADJ(6:5) | | 90 | | %lsc |
| 607 | Vt()min | Signal Level Monitoring 1: lower limit | referenced to Vscq() | | 40 | | %Vpp |
| 608 | Vt()max | Signal Level Monitoring 2: upper limit | referenced to Vscq() | | 130 | | %Vpp |
| Test C | Current ER | R | | | 1 | 1 | 11 |
| 701 | I(ERR) | Permissible Test Current | test mode activated | 0 | | 1 | mA |
| Bias (| Current Sou | urce and Reference Voltages | | | | 1 | 1 |
| 801 | IBN() | Bias Current Source | MODE(3:0) = 0x01, I(NC) vs. VDDS | 180 | 200 | 220 | μA |
| 802 | VPAH | Reference Voltage VPAH | referenced to GND | 45 | 50 | 55 | %VDD |
| 803 | V05 | Reference Voltage V05 | | 450 | 500 | 550 | mV |
| 804 | V025 | Reference Voltage V025 | | | 50 | | %V05 |
| Powe | r-Down-Res | set | | | 1 | | |
| 901 | VDDon | Turn-on Threshold | increasing voltage at VDD vs. GND | 3.7 | 4 | 4.3 | V |
| | | (power-on release) | ······································ | | | | |
| 902 | VDDoff | Turn-off Threshold (power-down reset) | decreasing voltage at VDD vs. GND | 3.2 | 3.5 | 3.8 | V |
| 903 | VDDhys | Threshold Hysteresis | VDDhys = VDDon - VDDoff | 0.3 | | | V |
| Clock | Oscillator | | | | , | 1 | |
| A01 | fclk() | Internal Clock Frequency | MODE(3:0) = 0x0A, fclk(NS) | 120 | 160 | 200 | kHz |
| Error | Signal Inpu | ut/Output, Pin ERR | | | 1 | 1 | 11 |
| B01 | Vs()lo | Saturation Voltage lo | vs. GND, I() = 4 mA | | | 0.4 | V |
| B02 | lsc() | Short-circuit Current lo | vs. GND; V(ERR) ≤ VDD V(ERR) > VTMon | 4 | | | mA mA |
| B03 | Vt()hi | Input Threshold Voltage hi | vs. GND | _ | | 2 | V |
| B04 | Vt()lo | Input Threshold Voltage Io | vs. GND | 0.8 | | | V |
| B05 | Vt()hys | Input Hysteresis | Vt()hys = Vt()hi - Vt()lo | 300 | 500 | | mV |
| B06 | lpu() | Input Pull-up Current | V() = 0VDD - 1 V, EPU = 1 | -400 | -300 | -200 | μA |
| B07 | Rpu() | Input Pull-Up Resistor | EPU=0 | | 500 | | kΩ |
| B08 | Vpu() | Pull-up Voltage | $V_{PU}() = VDD - V(), I() = -5 \mu A, EPU = 1$ | _ | | 0.4 | V |
| B09 | VTMon | Test Mode Activation Threshold | increasing voltage at ERR | _ | | VDD + | V |
| B10 | VTMoff | Test Mode Disabling Threshold | decreasing voltage at ERR | VDD + | | 1.0 | V |
| B11 | VTMhvs | Test Mode Hysteresis | VTMbys = VTMon - VTMoff | 0.15 | 03 | | V |
| B12 | llk() | | tristate or reversed supply voltage | 1 | -10 | -50 | ν 11Δ |
| | | Lounage Ourient | Inotate of reversed supply voltage | | 10 | -00 | μΛ |



Rev D2, Page 9/29

| ltem | Symbol | Parameter | Conditions | | | | Unit |
|--------|-------------|-----------------------------------|--|------|--------|------|----------|
| No. | | | | Min. | Тур. | Max. | |
| Suppl | y Switch an | d Reverse Polarity Protection VD | DDS, GNDS | | | | 0 |
| C01 | Vs() | Saturation Voltage | Vs(VDDS) = VDD - V(VDDS) | | | | |
| | | VDDS vs. VDD | I(VDDS) = -10 mA0 mA | | | 150 | mV |
| | | | I(VDDS) = -20 mA10 mA | | | 250 | mV |
| C02 | Vs() | Saturation Voltage | Vs(GNDS) = V(GNDS) - GND | | | 450 | |
| | | GNDS VS. GND | I(GNDS) = 0 mA10 mA | | | 150 | mV mV |
| Serial | Configurat | ion Interface SCI SDA | | | | 200 | IIIV |
| D01 | Vs()lo | Saturation Voltage Io | $ 1\rangle = 4 \text{ mA}$ | | | 400 | mV |
| D02 | | Short-circuit Current lo | | 4 | | 80 | mA |
| D03 | Vt()hi | Input Threshold Voltage hi | | | | 2 | V |
| D04 | Vt()Io | Input Threshold Voltage In | | 0.8 | | - | V |
| D05 | Vt()hvs | Input Hysteresis | Vt()hys = Vt()hi - Vt()lo | 300 | 500 | | mV |
| D06 | | Input Pull-up Current | V() = 0VDDS - 1V | -600 | -300 | -60 | uA |
| D07 | Vpu() | Input Pull-up Voltage | $V_{D}(0) = V_{D}DS - V(0, 10) = -5 \mu A$ | | 000 | 0.4 | V |
| D08 | fclk(SCL) | Clock Frequency at SCI | FNFAST = 0 | 60 | 80 | 100 | kHz |
| | | | ENFAST = 1 | 240 | 320 | 400 | kHz |
| D09 | tbusy()cfg | Duration of Startup Configuration | IBN not calibated, EEPROM access without | | | | |
| | | | read failure, time to outputs operational; | | | | |
| | | | ENFAST = 0 ENFAST = 1 | | 40 | 55 | ms |
| D10 | thusv()err | End Of I2C Communication: | IBN not calibrated: | _ | 20 | 00 | - 1110 |
| | lousy()en | Time Until I2C Slave Is Enabled | V(SDA) = 0 V | | 4 | 12 | ms |
| | | | V(SCL) = 0 V or arbitration lost | | indef. | | ms |
| | | | no EEPROM | | 45 | 135 | ms |
| D11 | 4-J() | Chart Of Master Astivity Or 100 | | _ | 95 | 285 | ms |
| | ta() | Start Of Master Activity On I2C | IBN not calibrated | 25 | 80 | 240 | 115 |
| | | | IBN calibrated to 200 µA | 64 | 80 | 120 | μs |
| D12 | td()i2c | Delay for I2C-Slave-Mode Enable | no EEPROM, V(SDA) = 0 V | | 4 | 6.2 | ms |
| Temp | erature Mor | nitoring | | | 1 | 1 | 11 |
| E01 | VTs | Temperature Sensor Voltage | VTs() = VDDS - V(PS), Tj = 27 °C, | 600 | 650 | 700 | mV |
| | | | Calibration Mode 3, no load | | | | |
| E02 | TCs | Temp. Co. of Temperature Sen- | | | -1.8 | | mV/K |
| | | sor Voltage | | _ | | | |
| E03 | VTth | Temperature Warning Activation | VTth() = VDDS - V(NS), Tj = 27 °C, | | | | |
| | | Theshold | CFGTA(3:0) = 0x00 | 260 | 310 | 360 | mV |
| | | | CFGTA(3:0) = 0x0F | 470 | 550 | 630 | mV |
| E04 | TCth | Temp. Co. Temperature Warning | | | 0.06 | | %/K |
| | | Activation Threshold | | | | | |
| E05 | Thys | Temperature Warning Hysteresis | | 4 | 12 | 20 | °C |
| E06 | ΔT | Relative Shutdown Temperature | $\Delta T = Toff - Twarn$ | 4 | 12 | 20 | °C |



Rev D2, Page 10/29

PROGRAMMING

| Register Map | Page 11 | Signal Condit GR12: GF1: | Coning CH1, CH2 (X3X6) Page 21 Gain Range CH1, CH2 (coarse) Gain Factor CH1 (fine) |
|------------------------|-------------------------------------|--------------------------------|---|
| Configuration | Interface Page 13 | GF2: | Gain Factor CH2 (fine) |
| ENFAST: | I ² C Fast Mode Enable | VOS12: | Offset Reference Source CH1. CH2 |
| FNSI | I^2C Slave Mode Enable | VDC1: | Intermediate Voltage CH1 |
| | Device ID of EEPROM providing the | VDC2 | Intermediate Voltage CH2 |
| DEVID. | chip configuration data (e.g. 0x50) | OR1. | Offset Range CH1 (coarse) |
| снкент | CRC of chip configuration data | OF1: | Offset Factor CH1 (fine) |
| | (address range 0x00 to 0x1E) | OR2: | Offset Range CH2 (coarse) |
| | Chin Belease | | Offset Factor CH2 (fine) |
| | Triatoto Function and | | Dhana Correction CH1 va. CH2 |
| INTRI. | And Change | FITIZ. | Phase Conection CH1 vs. CH2 |
| | Op. Mode Change | Signal Candit | |
| Calibratian | | | Cain Panga CH0 (acaraa) |
| | Diag Calibration | | Gain Range CH0 (Coalse) |
| | Bias Calibration | | Offect Deference Course CLIC |
| CFGTA: | Temperature Sensor Calibration | VUSU: | |
| | | ORU: | Offset Range CHU (coarse) |
| Operation Mod MODE: | des Page 16 Operation Mode | OF0: | Offset Factor CH0 (fine) |
| ENF: | Signal Filtering | Signal Level C | Controller Page 24 |
| | | ADJ: | Setup of ACO Output Function |
| Test Mode | Seite 17 | | |
| TMODE: | Test Mode Functions | Error Monitori | ng and Alarm Output Page 25 |
| TMEM: | Test Mode Memory Selection | EMTD: | Minimal Alarm Indication Time |
| | | EPH: | Alarm Input/Output Logic |
| Input Configu | ration and | EPU: | Alarm Output Pull-Up Enable |
| Signal Path M | ultiplexer Page 18 | EMASKA: | Error Mask For Alarm Indication (pin |
| INMODE: | Diff./Single-Ended Input Mode | | ERR) |
| RIN12: | I/V Mode and Input Resistance CH1, | EMASKE: | Error Mask For Protocol (EEPROM) |
| | CH2 | EMASKO: | Error Mask For Driver Shutdown |
| BIAS12: | Reference Voltage CH1, CH2 | | |
| RIN0: | I/V Mode and Input Resistance CH0 | ERR1: | Error Protocol: First Error |
| BIAS0: | Reference Voltage CH0 | ERR2 | Error Protocol: Last Error |
| MUXIN: | Input-To-Channel Assignment: | ERR3 | Error Protocol: History |
| | X3X6 to CH1, CH2 | Errito. | |
| INVZ: | Index Signal Inversion | | Driver Activation After Cycling Power |
| EAZ: | Index Comparator Enable | | Enver Admation Alter Cycling I Ower |
| MUXOUT: | Output Multiplexer (iC-MSB2 only) | | |
| BIASEX: | Input Reference Selection | | |

Input-to-output Feedthrough

BYP



Rev D2, Page 11/29

| OVERV | IEW | | | | | | | |
|--------------|----------------|---------------|---|---------------|--------------|-----------|-------------|---------|
| Adr | Bit 7 | Bit 6 | Bit 5 | Bit 4 | Bit 3 | Bit 2 | Bit 1 | Bit 0 |
| Configu | ration Interfa | ce | | L | 1 | | | |
| 0x00 | ENFAST | | | | DEVID(6:0) | | | |
| Calibrati | on | I | | | | | | |
| 0x01 | | CFGIE | 3N(3:0) | | | CFGT | A(3:0) | |
| Operatio | on Modes | | | | 1 | | | |
| 0x02 | NTRI | 1 | 0 | _ | | MOD | E(3:0) | |
| Input Co | onfiguration a | nd Signal Pat | h Multiplexer | : iC-MSB | | | | |
| 0x03 | EAZ | 0 | 0 | 0 | INVZ | INMODE | MUXII | N(1:0) |
| Input Co | onfiguration a | nd Signal Pat | h Multiplexer: | : iC-MSB2 | | | | |
| 0x03 | EAZ | | MUXOUT(2:0) | | INVZ | INMODE | MUXII | N(1:0) |
| Signal C | onditioning (| CH1, CH2 | | | | | | |
| 0x04 | | | GF2(4:0) | | | | GR12(2:0) | |
| 0x05 | | | | GF1 | (7:0) | | | |
| 0x06 | | | VDC1(4:0) | | | | GF1(10:8) | |
| 0x07 | | VDC2(2:0) | | | | VDC1(9:5) | | |
| 0x08 | OR1(0) | | | | VDC2(9:3) | | | |
| 0x09 | | | | OF1(6:0) | | | | OR1(1) |
| 0x0A | OF2 | (1:0) | OR2 | (1:0) | | OF1(| (10:7) | |
| 0x0B | | | | OF2 | (9:2) | | | |
| 0x0C | | | | PH12(6:0) | | | | OF2(10) |
| 0x0D | BIASE | X(1:0) | BYP | 1 | 1 | | PH12(9:7) | |
| 0x0E | ENF | BIAS12 | VOS1 | 2(1:0) | | RIN1 | 2(3:0) | |
| Signal L | evel Controlle | er | | | | | | |
| 0x0F | ADJ(0) | _ | 0 | 1 | 0 | 0 | 0 | 0 |
| 0x10 | | | | ADJ | (8:1) | | | |
| Signal C | onditioning (| CHO | | | | | | |
| 0x11 | | | GF0(4:0) | | | | GR0(2:0) | |
| 0x12 | | | OF0 | (5:0) | | | OR0 | (1:0) |
| 0x13 | 0 | BIAS0 | VOS | 0(1:0) | | RINC | 0(3:0) | |
| Error Mo | onitoring and | Alarm Output | t | | | | | |
| 0x14 | - | | | | EMASKA(6:0) | | | |
| 0x15 | TMOD | DE(1:0) | | EMTD(2:0) | | EPH | _ | — |
| 0x16 | _ | | | | EMASKO(6:0) | | | |
| 0x17 | | EMASI | <e(3:0)< td=""><td></td><td>ENSL</td><td>EPU</td><td>_</td><td>-</td></e(3:0)<> | | ENSL | EPU | _ | - |
| 0x18 | TMEM | PDMODE | _ | - | - | | EMASKE(6:4) | |
| 0x19 0x1A | | | | not de | efined | | | |
| 0x1B 0x1E | | | | OEM | Data | | | |
| Check S | um / Chip I | Release | | | | | | |
| 0x1F | • | | EEPRON | I: CHKSUM(7:0 |) / ROM: CHP | REL(7:0) | | |
| L I | | | | | | | | |



Rev D2, Page 12/29

| OVERV | IEW | | | | | | | |
|----------|---------|-------|--------|--------|-----------|-------|-----------|---------|
| Adr | Bit 7 | Bit 6 | Bit 5 | Bit 4 | Bit 3 | Bit 2 | Bit 1 | Bit 0 |
| Error Re | egister | | | | | | | |
| 0x20 | - | | | | ERR1(6:0) | | | |
| 0x21 | | | ERR | 2(5:0) | | | _ | _ |
| 0x22 | | ERR | 3(3:0) | | _ | _ | _ | ERR2(6) |
| 0x23 | - | _ | _ | _ | _ | | ERR3(6:4) | |

Table 4: Register layout



Rev D2, Page 13/29

SERIAL CONFIGURATION INTERFACE (EEPROM)

The serial configuration interface consists of the two pins SCL and SDA and enables read and write access to an EEPROM with I²C interface. The readout speed can be adjusted using register bit ENFAST.

| ENFAST | Adr 0x00, bit 7 |
|--------|---|
| Code | Function |
| 0 | Regular clock rate, f(SCL) approx. 80 kHz |
| 1 | High clock rate, f(SCL) approx. 320 kHz |
| Notes | For in-circuit programming bus lines SCL and SDA require pull-up resistors. For line capacitances to 170 pF, adequate values are: $4.7 k\Omega$ with clock frequency 80 kHz $2 k\Omega$ with clock frequency 320 kHz |
| | The pull-up resistors may not be less than $1.5 \text{ k}\Omega$. To separate the signals a ground line between SCL and SDA is recommended. iC-MSB requires a supply voltage during EEPROM programming (5 V to VDD). |

Table 5: Config. Interface Clock Frequency

Once the supply has been switched on (power down reset) the iC-MSB outputs are high impedance (tristate) until a valid configuration is read out from the EEPROM using device ID 0x50.

Bit errors in the 0x00 to 0x1E memory section are pinpointed by the CRC deposited in register CHK-SUM(7:0) (address 0x1F; the CRC polynomial used is "1 0001 1101").

Should no valid configuration data being available (incorrect CRC value or EEPROM missing), the readin process is repeated; the system aborts following a fourth faulty attempt and iC-MSB switches to I²C slave mode.

For devices loading valid configuration data from the EEPROM, the register bit ENSL decides for enabling the l^2C slave function.

| ENSL | Adr 0x17, bit 3 |
|------|---|
| Code | Function |
| 0 | Normal operation |
| 1 | I ² C Slave Mode Enable (Device ID 0x55) |

Table 6: Config. Interface Mode

The device ID for the EEPROM can be entered in register DEVID(6:0) (address 0x00), from which iC-MSB will take its configuration after exiting test mode (see page 17). The DEVID(6:0) stored therein is then accepted.

Example of CRC Calculation Routine

```
unsigned char ucDataStream = 0;
int iCRCPoly = 0x11D;
unsigned char ucCRC=0;
int i = 0;
ucCRC = 1; // start value !!!
for (iReg = 0; iReg<31; iReg ++) {
    ucDataStream = ucGetValue(iReg);
    for (i=0; i<=7; i++) {
        if ((ucCRC & 0x80) != (ucDataStream & 0x80))
            ucCRC = (ucCRC << 1) ^ iCRCPoly;
        else
            ucCRC = (ucCRC << 1);
        ucDataStream = ucDataStream << 1;
    }
}
```

EEPROM Selection

The following minimal requirements must be fulfilled:

- Operation from 3.3 to 5 V, I²C interface
- Minimal 512 bit, 64x8 (address range used is 0x00 to 0x3F)
- Support of *Page Write* with *Pages* of at least 4 bytes. Otherwise error events can not be saved to the EEPROM (EMASKE(9:0) = 0x000).
- Device ID 0x50 "1010000", no occupation of 0x55 (A2...A0=0). Otherwise iC-MSB is not accessible in I²C slave mode via 0x55 (ENSL = 0).

Device recommendation: Atmel AT24C01B, 128x8



I^2C Slave Mode (ENSL = 1)

In this mode iC-MSB behaves like an I²C slave with the device ID 0x55 and the configuration interface permits write and read accesses to iC-MSB's internal registers.

For chip release verification purposes an identification value is stored under ROM address 0x1F; a write access to this address is not permitted.

| CHPREL | Adr 0x1F, bit 7:0 (ROM) |
|--------|-----------------------------|
| Code | Chip Release |
| 0x00 | Not available |
| 0x04 | iC-MSB ^{SAFETY} v4 |
| 0x05 | iC-MSB ^{SAFETY} v5 |
| 0x25 | iC-MSB2 v5 |

Table 7: Chip Release

| NTRI | Adr 0x02, bit 7 |
|-------|--|
| Code | Function |
| 0 | Output drivers disabled |
| 1 | Setting the operating mode, output drivers active |
| Notes | NTRI is evaluated only during I ² C slave mode. |

Table 8: Tristate Function And Op. Mode Change

Rev D2, Page 14/29

| Register | Read access in I^2C slave mode (ENSL = 1) |
|-----------|---|
| Address | Content |
| 0x00-0x18 | Configuration: register addresses 0x00-0x18 |
| 0x19-0x1A | Not available |
| 0x1B-0x1E | OEM data: register addresses 0x1B-0x1E |
| 0x1F | Chip release (ROM) |
| 0x20-0x23 | Configuration: register addresses 0x20-0x23 |
| 0x24-0x37 | Not available |
| 0x38 | Configuration: register address 0x18 |
| 0x39-0x3A | Not available |
| 0x3B-0x3E | OEM data: register addresses 0x1B-0x1E |
| 0x3F | Chip release (ROM) |
| 0x40-0x43 | Current error memory |
| 0x44-0x7F | Not available |

Table 9: RAM Read Access

| Register | Write access in I^2C slave mode (ENSL = 1) |
|-----------|--|
| Address | Access and conditions |
| 0x00 | Changes possible, no restrictions |
| 0x01 | Changes possible (wrong entries for CFGIBN can limit functions) |
| 0x02 | Bit $7 = 0$ (NTRI): changes to bits (6:0) permitted A change of operating mode follows only on writing Bit $7 = 1$ (NTRI); when doing so changes to bits (6:0) are not permitted. |
| 0x03-0x16 | Changes possible, no restrictions |
| 0x17 | Bit 3 = 1 (ENSL): |
| | changes to bits (7:4) and (2:0) permitted |
| 0x18 | Changes possible, no restrictions |
| 0x19-0x1A | Not available |
| 0x1B-0x1E | Changes possible, no restrictions |
| others | No changes permitted |

Table 10: RAM Write Access



Rev D2, Page 15/29

BIAS SOURCE AND TEMPERATURE SENSOR CALIBRATION

Bias Source Calibration

The calibration of the bias current source in operation mode *Calibration 1* (Tab. 13) is prerequisite for adherence to the given electrical characteristics and also instrumental in the determination of the chip timing (e.g. SCL clock frequency). For setup purposes the IBN value is measured using a $10 \text{ k}\Omega$ resistor by pin VDDS connected to pin NC. The setpoint is $200 \,\mu\text{A}$ which is equivalent to a measurement voltage of 2 V.

| CFGIBN | Adr 0x01, bit 7:4 | | |
|--------|----------------------------|--------|---------------------------|
| Code k | $IBN \sim \frac{31}{39-k}$ | Code k | $IBN \sim rac{31}{39-k}$ |
| 0x0 | 79% | 0x8 | 100 % |
| 0x1 | 81 % | 0x9 | 103 % |
| 0x2 | 84% | 0xA | 107 % |
| 0x3 | 86 % | 0xB | 111 % |
| 0x4 | 88 % | 0xC | 115 % |
| 0x5 | 91 % | 0xD | 119% |
| 0x6 | 94 % | 0xE | 124 % |
| 0x7 | 97 % | 0xF | 129% |

Table 11: Bias Current Source Calibration

Temperature Sensor

The temperature monitor is calibrated in operating mode *Calibration Mode 3*.

To set the required warning temperature T_2 the temperature sensor voltage VTs at which the warning is generated is first determined. To this end a voltage ramp from VDDS towards GNDS is applied to pin PS until pin ERR triggers an error message (for EMASKA = 0x20 and EMTD = 0x00).

Example: VTs(T_1) is ca. 650 mV, measured from VDDS versus PS, with $T_1 = 25 \text{ °C}$;

The necessary activation threshold voltage VTth(T_1) is then calculated. The required warning temperature T_2 , temperature coefficients TCs and TCth (see Electrical Characteristics, Section E) and measurement value VTs(T_1) are entered into this calculation:

$$VTth(T_1) = \frac{VTs(T_1) + TCs \cdot (T_2 - T_1)}{1 + TCth \cdot (T_2 - T_1)}$$

Example: For $T_2 = T_1 + 100 \text{ K}$, VTth(T_1) must be programmed to 443 mV.

Activation threshold voltage VTth(T₁) is provided for a high impedance measurement ($10 M\Omega$) at output pin NS (measurement versus VDDS) and must be set by programming CFGTA(3:0) to the calculated value.

Example: Altering VTth(T_1) from 310 mV (measured with CFGTA(3:0)= 0x0) to 443 mV is equivalent to 143 %, the closest value for CFGTA is 0x9;

| CFGTA | Adr 0x01, bit 3:0 | | |
|--------|--|--------|------------------------------|
| Code k | VTth $\sim rac{65+3k}{65}$ | Code k | VTth $\sim \frac{65+3k}{65}$ |
| 0x0 | 100 % | 0x8 | 140 % |
| 0x1 | 105 % | 0x9 | 145 % |
| 0x2 | 110 % | 0xA | 150 % |
| 0x3 | 115 % | 0xB | 155 % |
| 0x4 | 120 % | 0xC | 160 % |
| 0x5 | 125 % | 0xD | 165 % |
| 0x6 | 130 % | 0xE | 170 % |
| 0x7 | 135 % | 0xF | 175 % |
| Notes | With CFGTA = $0xF$ Toff is 80 °C typ., with CFGTA = $0x0$ Toff is 155 °C typ. | | |

Table 12: Calibration of Temperature Monitoring



Rev D2, Page 16/29

OPERATING MODES

In order to calibrate iC-MSB, compensate for the input signals and test iC-MSB the mode of operation must be changed. The output function changes according

to the various operating modes; the line drivers and protection against reverse polarity facility are only active in normal mode.

| | | | 11.00 | | | | | |
|-----------|--|----------------------|-----------------|-----------------|-----------------|-----------------|-----------------|---------|
| MODE(3:0) | | Addr. 0x02; | bit 3:0 | | | | | |
| BYP | | Addr. 0x0D; | bit 5 | | | | | |
| Code | Operating Mode | Pin PS | Pin NS | Pin PC | Pin NC | Pin PZ | Pin NZ | Pin ERR |
| 0x00 | Normal operation | PS | NS | PC | NC | PZ | NZ | ERR |
| 0x01 | Calibration 1 | TANA0(2) | VREFI0 | VREFI12 | IBN | PZI | NZI | ERR |
| 0x02 | Calibration 2 | PCH1 | NCH1 | PCH2 | NCH2 | VDC1 | VDC2 | — |
| 0x03 | iC-Haus Test 1 | VPAH | VPD | — | CGUCK | IPF | V05 | IERR |
| 0x04 | iC-Haus Test 2 | PS_out | NS_out | PC_out | NC_out | PZ_out | NZ_out | IERR |
| 0x05 | iC-Haus Test 3 | PS_out | NS_out | PC_out | NC_out | PZ_out | NZ_out | ERR |
| 0x06 | iC-Haus Test 4, BYP = 0 iC-Haus Test 4, BYP = 1 | TANA12(0) X4 | TANA12(1) X6 | TANA12(2) X3 | TANA12(3) X5 | TANA12(4) X1 | TANA12(5) X2 | IERR |
| 0x07 | Calibration 3 | VTs | VTth | — | — | _ | — | ERR |
| 0x08 | Saturation low | SCL, SDA and ERR low | | | | | | |
| 0x09 | — | — | _ | — | — | — | — | — |
| 0x0A | iC-Haus Test 5 | TP | CLK6 | — | — | _ | — | — |
| 0x0B | — | — | _ | — | — | _ | — | — |
| 0x0C | _ | — | _ | _ | — | _ | — | — |
| 0x0D | — | — | _ | — | - | — | - | — |
| 0x0E | IDDQ-Test | | All PU/PE | o resistors, os | cillator and su | oply voltage de | eactivated | |
| 0x0F | — | — | _ | — | — | — | - | _ |

Table 13: Selection of Operating Modes

Calibration Op. Modes

In *Calibration Mode 1* the user can measure the BIAS current (IBN), input amplifier reference potential VREFI and the analog signals from channel 0 following signal conditioning (PCH0 and NCH0).

In *Calibration Mode 2* the conditioned signals from channels 1 and 2 are output (PCH1, NCH1, PCH2 and NCH2). In addition the intermediate potentials of the compensating circuits are also available for CH1 (VDC1) and CH2 (VDC2).

In *Calibration Mode* 3 the internal temperature monitoring signals are provided.

Special Device Test Functions

IDDQ-Test, Saturation Low, Saturation High, and Test 1 to 5 are test modes for iC-Haus device tests. With an activated bypass (BYP = 1), mode *iC-Haus Test 4* permits the direct feedthrough of X1 - X6 input signals to the output pins; in this instance the output impedance is high-ohmic. Furthermore, if the input voltage divider is selected (by RINx = 1--1), it reduces the signal amplitudes to approx. 7/8.

Signal Filter

iC-MSB has a noise limiting signal filter to filter the conditioned analog signals. This can be activated using ENF.

| ENF | Adr 0x0E, bit 7 |
|------|---------------------------|
| Code | Function |
| 0 | Noise limiter deactivated |
| 1 | Noise limiter activated |

Table 14: Signal Filtering



Rev D2, Page 17/29

TEST MODE

iC-MSB switches to test mode when a voltage greater than VTMon is applied to pin ERR (precondition: TMODE(0) = 1). In response iC-MSB transmits its configuration settings as current-modulated data using error signal I/O pin ERR either directly from the RAM (for TMEM = 1) or after re-reading the EEPROM (for TMEM = 0).

| ТМЕМ | Adr 0x18, bit 7 |
|------|---------------------|
| 0 | EEPROM contents |
| 1 | iC-MSB RAM contents |

Table 15: Test Mode Memory Selection

Should the voltage at the ERR pin fall below VTMoff test mode is terminated and data transmission aborted.

The clock rate for the data output is determined by ENFAST. Two clock rates can be selected: 780 ns for ENFAST = 1 or $3.125 \,\mu$ s for ENFAST = 0 (see Electrical Characteristics, D08, for clock frequency and tolerances).

Data is output in Manchester code via two clock pulses per bit. To this end the lowside current source switches between a Z state (OFF = 0 mA) and an L state (ON = 2 mA).

The bit information lies in the direction of the current source switch:

Zero bit: change of state $Z \rightarrow L$ (OFF to ON) One bit: Change of state $L \rightarrow Z$ (ON to OFF)

Transmission consists of a start bit (a one bit), 8 data bits and a pause interval in Z state (the timing is identical with an EEPROM access via the I^2C interface).

Example: byte value = 1000 1010 Transmission including the start bit: 1 1000 1010 In Manchester code: LZ LZZL ZLZL LZZL LZZL

Decoding of the data stream:

When test mode is quit with TMODE > 0, then iC-MSB again reads out its configuration from the EEP-ROM, accessible at the device ID filed to DEVID(6:0) of adr 0x00. In TMODE = 0x00 the EEPROM is read completely; in all other cases only the address range 0x00 to 0x21 is read to keep the configuration time for device testing short. When test mode is quit with TMODE = 0x00 iC-MSB continues operation without any interruption.

| TMODE | Adr 0x15, bit 7:6 | |
|-------|---|--------------------------------|
| Code | Function during test mode | Function following test mode |
| 00 | Normal operation | Normal operation |
| 01 | TMEM = 0: Transmission of EEPROM data, address range 0x1B-0x7F | Repeated read out of EEPROM |
| | TMEM = 1: Transmission of RAM data, address range 0x3B-0x43 | |
| 10 | Normal operation | Repeated read out of EEPROM |
| 11 | Transmission of EEPROM data, address range 0x0-0x7F | Repeated read out of EEPROM |

Table 16: Test Mode Functions



Figure 1: Example circuit for the decoding and conversion of the current-modulated signals to logic levels.



Rev D2, Page 18/29

INPUT CONFIGURATIONS

Input Configurations

All input stages are configured as instrumentation amplifiers and thus directly suitable for differential input signals. Referenced input signals can be processed as an option; in this mode input X2 acts as a reference.

| INMODE | Adr 0x03, bit 2 |
|--------|---|
| Code | Function |
| 0 | Differential input signals |
| 1 | Single-ended input signals * |
| Note | * Input X2 is reference for all inputs. |

Table 17: Input Signal Mode

Both current and voltage signals can be processed as input signals, selected using RIN12(0) and RIN0(0).

In I Mode an input resistor Rin() becomes active at each input pin, converting the current signal into a voltage signal. Input resistance Rin() consists of a pad wiring resistor and resistor Rui() which is linked to the adjustable bias voltage source VREFin(). The following table shows the possible selections, with Rin() giving the typical resulting input resistance (see Electrical Characteristics for tolerances). The input resistor should be set in such a way that intermediate potentials VDC1 and VDC2 lie between 125 mV and 250 mV (verifiable in *Calibration Mode 2*).

In V Mode an optional voltage divider can be selected which reduces unacceptably large input amplitudes to ca. 25%. The circuitry is equivalent to the resistor chain in I Mode; the pad wiring resistor is considerably larger here, however.

| RIN12 | Adr 0x0E, bit 3: | Adr 0x0E, bit 3:0 | | | |
|-------|------------------|-------------------|---------------|--|--|
| RIN0 | Adr 0x13, bit 3: | 0 | | | |
| Code | Nominal Rin() | Intern Rui() | I/V Mode | | |
| -000 | 1.7 kΩ | 1.6 kΩ | current input | | |
| -010 | 2.5 kΩ | 2.3 kΩ | current input | | |
| -100 | 3.5 kΩ | 3.2 kΩ | current input | | |
| -110 | 4.9 kΩ | 4.6 kΩ | current input | | |
| 1—1 | 20 kΩ | 5 kΩ | voltage input | | |
| 0—1 | high | 1 MΩ | voltage input | | |
| | impedance | | | | |

Table 18: I/V Mode and Input Resistance

| BIAS12 | Adr 0x0E, bit 6 | |
|--------|-----------------|----------------------------------|
| BIAS0 | Adr 0x13, bit 6 | |
| Code | VREFin() | Type of sensor |
| 0 | 2.5 V) | Lowside sink current (I Mode) |
| 1 | 1.5 V) | Highside current source (I Mode) |

Table 19: Reference Voltage

| BIASEX | Adr 0x0D, bit 7:6 | | |
|--------|---|-----------------------------------|--|
| Code | VREFin() Signal at X2 | | |
| 0- | internal | Neg. Zero Signal (Index -), input | |
| 10 | internal * Ref. Voltage VREFin12, output | | |
| 11 | external* Ref. Voltage VREFin, input | | |
| Note | *) The voltage at X2 is reference for all inputs. | | |

Table 20: Input Reference Selection



Figure 2: Input instrumentation amplifier and signal conditioning



Rev D2, Page 19/29

SIGNAL PATH MULTIPLEXING: iC-MSB^{SAFETY}



Figure 3: Multiplexer Schematics

The signals for index channel CH0 are connected up to pins X1 and X2. Pins X3 to X6 are allocated to internal channels CH1 and CH2 via MUXIN. INMODE can be activated for referenced input signals; this then selects X2 as the reference input. For output purposes INVZ allows the index signal phase to be inverted.

| MUXIN | 0x03, bit 1:0 | | | | |
|-------|---------------|-------|-------|-------|--|
| Code | PCH1i | NCH1i | PCH2i | NCH2i | |
| 00 | X4 | X6 | X3 | X5 | |
| 01 | X4 | X6 | X5 | X5 | |
| 10 | X4 | X5 | Х3 | X6 | |
| 11 | X4 | X3 | X5 | X6 | |

Table 21: Input Multiplexer for INMODE = 0

| MUXIN | 0x03, bit 1:0 | | | | |
|-------|-------------------------|----|----|----|--|
| Code | PCH1i NCH1i PCH2i NCH2i | | | | |
| -0 | X4 | X2 | X3 | X2 | |
| -1 | X4 | X2 | X5 | X2 | |

Table 22: Input Multiplexer for INMODE = 1

| Adr 0x03, bit 7 |
|-------------------|
| Function |
| Comparator bypass |
| Comparator active |
| |

Table 23: Index Output

EAZ permits the activation of an analog comparator for index channel CH0.

| INVZ | Adr 0x03, bit 3 | |
|------|-----------------|--------|
| Code | PZ_out | NZ_out |
| 0 | PCH0o | NCH0o |
| 1 | NCH0o | PCH0o |

Table 24: Index Signal Inversion



Rev D2, Page 20/29

EXTENDED SIGNAL PATH MULTIPLEXING: iC-MSB2 (not for safety applications)



Figure 4: Multiplexer Schematics

The signals for index channel CH0 are connected up to pins X1 and X2. Pins X3 to X6 are allocated to internal channels CH1 and CH2 via MUXIN. INMODE can be activated for referenced input signals; this then selects X2 as the reference input. For output purposes INVZ allows the index signal phase to be inverted.

| MUXIN | 0x03, bit 1:0 | l i i i i i i i i i i i i i i i i i i i | | |
|-------|---------------|---|-------|-------|
| Code | PCH1i | NCH1i | PCH2i | NCH2i |
| 00 | X4 | X6 | X3 | X5 |
| 01 | X4 | X6 | X5 | X5 |
| 10 | X4 | X5 | Х3 | X6 |
| 11 | X4 | X3 | X5 | X6 |

Table 25: Input Multiplexer for INMODE = 0

| MUXIN | 0x03, bit 1:0 | | | |
|-------|---------------|-------|-------|-------|
| Code | PCH1i | NCH1i | PCH2i | NCH2i |
| -0 | X4 | X2 | X3 | X2 |
| -1 | X4 | X2 | X5 | X2 |

Table 26: Input Multiplexer for INMODE = 1

| INVZ | Adr 0x03, bit 3 | |
|------|-----------------|--------|
| Code | PZ_out | NZ_out |
| 0 | PCH0o | NCH0o |
| 1 | NCH0o | PCH0o |

Table 27: Index Signal Inversion

EAZ permits the activation of an analog comparator for index channel CH0.

| EAZ | Adr 0x03, bit 7 |
|------|-------------------|
| Code | Function |
| 0 | Comparator bypass |
| 1 | Comparator active |

Table 28: Index Output

| MUXOUT | Adr 0x03, bit 6:4 | | | | |
|--------|--------------------|--------|-----------|------------|--|
| Code | PS_Out | NS_Out | PC_Out | NC_Out | |
| 000 | Char | nel 1 | Channel 2 | | |
| 010 | Char | nel 1 | Channel | 2 inverted | |
| 100 | Channel 1 inverted | | Channel 2 | | |
| 110 | Channel 1 inverted | | Channel | 2 inverted | |
| 001 | Channel 2 | | Char | nel 1 | |
| 011 | Channel 2 | | Channel | 1 inverted | |
| 101 | Channel 2 inverted | | Channel 1 | | |
| 111 | Channel 2 inverted | | Channel | 1 inverted | |

Table 29: Output Multiplexer



Rev D2, Page 21/29

SIGNAL CONDITIONING CH1, CH2

The voltage signals necessary for the conditioning of channels 1 and 2 can be measured in operation mode *Calibration 2*.

Gain Settings CH1, CH2

The gain is set in four stages:

1. The sensor supply tracking is shut down and the constant current source for the ACO output set to a suitable output current (register ADJ; current value close to the later operating point).

2. The coarse gain is selected so that the differential signal amplitudes of ca. 1 Vpp are produced (signal Px vs. Nx, see Figure below).

3. Using fine gain factor GF2 the CH2 signal amplitude is then adjusted to 1 Vpp.

4. The CH1 signal amplitude can then be adjusted to the CH2 signal amplitude via fine gain factor GF1.



Figure 5: Definition of 1 Vpp signal. Termination R0 must be high-ohmic during all *Test* and *Calibration* modes.

| GR12 | Adr 0x04, bit 2:0 | |
|------|----------------------|----------------------|
| Code | Range with RIN12=0x9 | Range with RIN12≠0x9 |
| 0x0 | 0.5 | 2.0 |
| 0x1 | 1.0 | 4.1 |
| 0x2 | 1.3 | 5.3 |
| 0x3 | 1.7 | 6.7 |
| 0x4 | 2.2 | 8.7 |
| 0x5 | 2.6 | 10.5 |
| 0x6 | 3.3 | 13.2 |
| 0x7 | 4.0 | 16.0 |

Table 30: Gain Range CH1, CH2

| GF2 | Adr 0x04, bit 7:3 |
|------|-------------------------------------|
| Code | Factor |
| 0x00 | 1.00 |
| 0x01 | 1.06 |
| | 6.25 ^{GF2} / ₃₁ |
| 0x1F | 6.25 |

Table 31: Fine Gain Factor CH2

| GF1 | Adr 0x06, bit 2:0, Adr 0x05, bit 7:0 |
|-------|---------------------------------------|
| Code | Factor |
| 0x000 | 1.0 |
| 0x001 | 1.0009 |
| | 6.25 ^{GF1} / ₁₉₈₄ |
| 0x7FF | 6.6245 |

Table 32: Fine Gain Factor CH1



Offset Calibration CH1, CH2

In order to calibrate the offset the reference source must first be selected using VOS12. Two fixed voltages and two dependent sources are available for this purpose. The fixed voltage sources should be selected for external sensors which provide stable, self-regulating signals.

So that photosensors can be operated in optical encoders iC-MSB tracks changes in offset voltages via the signal-dependent source VDC when used in conjunction with the controlled sensor current source for LED supply (pin ACO). The VDC potential automatically tracks higher DC photocurrents. To this end intermediate potentials VDC1 and VDC2 must be adjusted to a minimal AC ripple using the selectable k factor (this calibration must be repeated when the gain setting is altered).

The feedback of pin voltage V(ACO) fulfills the same task as source VDC when MR bridge sensors are supplied by the controlled power supply output. In this instance the VDC intermediate voltages do not need adjusting.

| VOS12 | Adr 0x0E, bit 5:4 |
|-------|----------------------|
| Code | Type of source |
| 0x0 | 0.05 · V(ACO) |
| 0x1 | 0.5 V |
| 0x2 | 0.25 V |
| 0x3 | VDC (ie. VDC1, VDC2) |

Table 33: Offset Reference Source CH1, CH2

| VDC1 | Adr 0x07, bit 4:0; Adr 0x06, bit 7:3 |
|-------|---|
| VDC2 | Adr 0x08, bit 6:0; Adr 0x07, bit 7:5 |
| Code | $VDC = k \cdot VPi + (1 - k) \cdot VNi$ |
| 0x000 | k = 0.33 |
| 0x001 | k = 0.33032 |
| | $k = 0.33 + MP2 \cdot 0.00032$ |
| 0x3FF | k = 0.66 |

Table 34: Intermediate Voltages CH1, CH2

Rev D2, Page 22/29

The calibration range for the CH1/CH2 offset is dependent on the selected VOS12 source and is set using OR1 and OR2. Both sine and cosine signals are then calibrated using factors OF1 and OF2. The calibration target is reached when the DC fraction of the differential signals PCHx versus NCHx is zero.

| OR1 | Adr 0x09, bit 0; Adr 0x08, bit 7 |
|------|----------------------------------|
| OR2 | Adr 0x0A, bit 5:4 |
| Code | Range |
| 0x0 | x1 |
| 0x1 | x2 |
| 0x2 | x6 |
| 0x3 | x12 |

Table 35: Offset Range CH1, CH2

| OF1 | Adr 0xA, bit 3:0; Ad | dr 0x9, bit 7:1 | |
|-------|--|-----------------|----------------|
| OF2 | Adr 0xC, bit 0; Adr 0xB, bit 7:0; Adr 0xA, bit 7:6 | | |
| Code | Factor | Code | Factor |
| 0x000 | 0 | 0x400 | 0 |
| 0x001 | 0.00098 | 0x401 | -0.00098 |
| | 0.00098 · OFx | | -0.00098 · OFx |
| 0x3FF | 1 | 0x7FF | -1 |

Table 36: Offset Factors CH1, CH2

Phase Correction CH1 vs. CH2

The phase shift between CH1 and CH2 can be adjusted using parameter PH12. Following phase calibration other calibration parameters may have to be adjusted again (those as amplitude compensation, intermediate potentials and offset voltages).

| PH12 | Adr 0xD, bit 2:0; Adr 0xC, bit 7:1 | | |
|-------|------------------------------------|-------|------------------|
| Code | Correction angle | Code | Correction angle |
| 0x000 | +0 | 0x200 | -0 |
| 0x001 | +0.0204 | 0x201 | -0.0204 |
| | +0.0204 · PH12 | | -0.0204 · PH12 |
| 0x1FF | +10.42 | 0x3FF | -10.42 |

Table 37: Phase Correction CH1 vs. CH2



Rev D2, Page 23/29

SIGNAL CONDITIONING CH0

The voltage signals needed to calibrate channel 0 are available in *Calibration Mode 1*.

Gain Settings CH0

Parallel to the conditioning process for the CH1 and CH2 signals the CH0 gain is set in the following stages:

1. The sensor supply tracking unit is shut down and the constant current source for the ACO output set to the same output current as in the compensation of CH1 and CH2 (register ADJ; current value close to the later operating point).

2. The coarse gain is selected so that a differential signal amplitude of ca. 1 Vpp is produced internally (signal PCHx versus NCHx).

3. GF0 then permits fine gain adjustment to 1 Vpp.

| GR0 | Adr 0x11, bit 2:0 | |
|------|---------------------|---------------------|
| Code | Range with RIN0=0x9 | Range with RIN0≠0x9 |
| 0x0 | 0.5 | 2.0 |
| 0x1 | 1.0 | 4.1 |
| 0x2 | 1.3 | 5.3 |
| 0x3 | 1.7 | 6.7 |
| 0x4 | 2.2 | 8.7 |
| 0x5 | 2.6 | 10.5 |
| 0x6 | 3.3 | 13.2 |
| 0x7 | 4.0 | 16.0 |

Table 38: Gain Range CH0

| GF0 | Adr 0x11, bit 7:3 |
|------|------------------------|
| Code | Factor |
| 0x00 | 1.00 |
| 0x01 | 1.06 |
| | 6.25 ^{GFZ} 31 |
| 0x1F | 6.25 |

Table 39: Fine Gain Factor CH0

Offset Calibration CH0

To calibrate the offset the source of supply must first be selected using VOS0 (see Offset Calibration CH1 and CH2 for further information). For the CH0 path the dependent source VDC is identical to source VDC1.

| VOSZ | Adr 0x13, bit 5:4 |
|------|-------------------|
| Code | Source |
| 0x0 | 0.05 · V(ACO) |
| 0x1 | 0.5 V |
| 0x2 | 0.25 V |
| 0x3 | VDC (ie. VDC1) |

Table 40: Offset Reference Source CH0

| OR0 | Adr 0x12, bit 1:0 |
|------|-------------------|
| Code | Range |
| 0x0 | x1 |
| 0x1 | x2 |
| 0x2 | x6 |
| 0x3 | x12 |

Table 41: Offser Range CH0

| OF0 | Adr 0x12, bit 7:2 | | |
|------|-------------------|------|---------------|
| Code | Factor | Code | Factor |
| 0x00 | 0 | 0x20 | 0 |
| 0x01 | 0.0322 | 0x21 | -0.0322 |
| | 0.0322 · OFZ | | -0.0322 · OFZ |
| 0x1F | 1 | 0x3F | -1 |

Table 42: Offset Factor CH0



Rev D2, Page 24/29

SIGNAL LEVEL CONTROL and SIGNAL MONITORING

Via the controlled sensor current source (pin ACO) iC-MSB can keep the output signals for the ensuing sine/digital converter constant regardless of temperature and aging effects by tracking the sensor supply.

Both the controller operating range and input signal amplitude for the controller are monitored and can be enabled for error messaging. A constant current source can be selected for the ACO output when setting the signal conditioning; the current range for the highside current source is adjusted using ADJ(6:5).



Figure 6: Signal level monitoring with square control (example for ADJ(8:0) = 0x19; see Elec. Char. Nos.607 and 608 regarding Vt()min resp. Vt()max)

| ADJ (8:7) | Adr 0x10, bit 7:6 |
|-----------|----------------------------------|
| Code | Function |
| 00 | Sine/cosine square control |
| 01 | Sum control |
| 10 | Constant current source |
| 11 | Not permitted (device test only) |

Table 43: Controller Operating Modes

| ADJ (6:5) | Adr 0x10, bit 5:4 |
|-----------|-------------------|
| Code | Function |
| 00 | 5 mA - Range |
| 01 | 10 mA - Range |
| 10 | 25 mA - Range |
| 11 | 50 mA - Range |

Table 44: ACO Output Current Range (applies for control modes and constant current source)

| ADJ (4:0) | Adr 0x10, bit 3:0; Adr 0x0F, bit 7 | | |
|-----------|--|--|--|
| Code | Square control ADJ(8:7) = 00 | | |
| 0x00 | Vpp() ca. 300 mV (60 %) | | |
| 0x01 | Vpp() ca. 305 mV (61 %) | | |
| | Vpp() $\approx 300 mV_{\overline{77-(1.25*Code)}}^{77}$ | | |
| 0x19 | Vpp() ca. 500 mV (98 %) | | |
| 0x1F | Vpp() ca. 600 mV (120 %) | | |

Table 45: Vpp Setpoint For Square Control

| ADJ (4:0) | Adr 0x10, bit 3:0; Adr 0x0F, bit 7 | | |
|-----------|--|--|--|
| Code | Sum control ADJ(8:7) = 01 | | |
| 0x00 | VDC1 + VDC2 ca. 245 mV | | |
| 0x01 | VDC1 + VDC2 ca. 249 mV | | |
| | VDC1 + VDC2 $\approx 245 mV \frac{77}{77 - (1.25 * Code)}$ | | |
| 0x1F | VDC1 + VDC2 ca. 490 mV | | |

Table 46: DC Setpoint For Sum Control

| ADJ (4:0) | Adr 0x10, bit 3:0; Adr 0x0F, bit 7 | |
|-----------|--|--|
| Code | Constant current source ADJ(8:7) = 10 | |
| 0x00 | I(ACO) ca. 3.125% lsc(ACO) | |
| 0x01 | I(ACO) ca. 6.25% Isc(ACO) | |
| | $I(ACO) \approx 3.125\% * (Code + 1) * Isc(ACO)$ | |
| 0x1F | I(ACO) ca. 100% lsc(ACO) | |
| Notes | See Elec. Char. No. 602 for Isc(ACO) | |

Table 47: I(ACO) With Constant Current Source



Rev D2, Page 25/29

ERROR MONITORING AND ALARM OUTPUT

The following table gives the errors which can both be recognized by iC-MSB and enabled either for messaging, output shutdown or protocol in the EEPROM. Mask EMASKA stipulates that errors should be signaled at pin ERR, mask EMASKO determines whether the line driver outputs are to be shutdown or not (with PDMODE setting a renewed power-on) and mask EMASKE governs the storage of error events in the EEPROM.

| EMASKA | Adr 0x14, bit 6:0 |
|--------|--|
| EMASKO | Adr 0x16, bit 6:0 |
| EMASKE | Adr 0x18, bit 2:0; Adr 0x17, bit 7:4 |
| Bit | Error Event |
| 6 | Configuration error*: SDA or SCL pin error, no Ack signal from EEPROM or invalid check sum |
| 5 | Excessive temperature warning |
| 4 | External system error |
| 3 | Level controller out of range (max. limit) |
| 2 | Level controller out of range (min. limit) |
| 1 | Signal clipping (excessive input level) |
| 0 | Loss of signal (poor input level or CH1/CH2 phase out of range) |
| Note | *) The line drivers remain high impedance (tristate) when cycling power. |

Table 48: Error Event Masks

Error Protocol

Out of the errors pinpointed by EMASKE both the first (ERR1) and last error (ERR2) which occur after the iC-MSB is turned on are stored in the EEPROM. The EEPROM also has a memory area in which all occurring errors can be stored (ERR3). Only the fact that an error has occurred can be recorded, with no information as to the time and frequency of that error given. The EEPROM memory can be used to statistically evaluate the causes of system failure, for example.

| _ | |
|------|--------------------------------------|
| ERR1 | Adr 0x20, bit 6:0 |
| ERR2 | Adr 0x22, bit 0; Adr 0x21, bit 7:2 |
| ERR3 | Adr 0x23, bit 2:0; Adr 0x22, bit 7:4 |
| Bit | Error Event |
| 9:0 | Assignation according to EMASKE |
| | |
| Code | Function |
| 0 | No event |
| 1 | Registered error event |
| | |

Table 49: Error Protocol

I/O pin ERR

Pin ERR is operated by a current-limited open drain output driver and has an internal pull-up which can be shutdown. The ERR pin also acts as an input for external system error messaging and for switching iC-MSB to test mode for which a voltage of greater than VTMon must be applied. Interpretation of external system error messaging and the phase length of the message output can be set using EPH; the minimum signaling duration for internal errors is adjusted using EMTD(2:0).

| EPU | Adr 0x17, bit 2 |
|------|---------------------------------|
| Code | Function |
| 0 | without internal pull-up at ERR |
| 1 | internal pull-up at ERR active |

Table 50: Alarm Output Pull-up Enable

| PDMODE | Adr 0x18, bit 6 |
|--------|---|
| Code | Function |
| 0 | Line driver active when no error persists |
| 1 | Line driver active after power-on |

Table 51: Driver Activation

| EPH | Adr 0x15, bit 2 | |
|------|--------------------------------|---|
| Code | ERR pin function | Ext. error message |
| 0 | with error low, otherwise Z | with error low, otherwise pull-up active |
| 1 | with error Z, otherwise low | with error pull-up active, otherwise low |

Table 52: Alarm Input/Output Logic

| EMTD | Adr 0x15, bit 5:3 | | |
|------|-------------------|------|-----------------|
| Code | Indication Time | Code | Indication Time |
| 0x0 | 0 ms | 0x4 | 50 ms |
| 0x1 | 12.5 ms | 0x5 | 62.5 ms |
| 0x2 | 25 ms | 0x6 | 75 ms |
| 0x3 | 37.5 ms | 0x7 | 87.5 ms |

Table 53: Minimum Alarm Indication Time



Rev D2, Page 26/29

TEMPERATURE MONITORING

iC-MSB has an integrated temperature monitor. If the temperature threshold is exceeded an excessive temperature message is generated which is processed in the temperature monitor block. The warning threshold

can be signaled at pin ERR or used to shut down the line drivers. If temperature $Toff = Twarn + \Delta T$ is exceeded the line drivers are shut down independent of EMASKO(6:0).

REVERSE POLARITY PROTECTION

The line drivers in iC-MSB are protected against reverse polarity and short-circuiting. A defective device cable or one wrongly connected cause damage neither to iC-MSB nor to the components protected against reverse polarity by VDDS and GNDS. The following pins are also reverse polarity protected: PC, NC, PS, NS, PZ, NZ, ERR, VDD, GND and ACO (as long as GNDS is only loaded versus VDDS). The maximum voltage difference between the pins should not be greater than 6 V, the exception here being pin ERR.



APPLICATION HINTS

Connecting MR sensor bridges for safety-related applications For safety-related applications iC-MSB^{SAFETY} requires an external overvoltage protection of supply VDD (Zener diode with fuse, for instance) and external pull-down resistors at the inputs X3 to X6 towards GNDS (of up to 100 kΩ).



Figure 7: Example circuit for safety-related applications with iC-MSB^{SAFETY}.

PLC Operation

There are PLCs with a remote sense supply which require longer for the voltage regulation to settle. At the same time the PLC inputs can have high-impedance resistances versus an internal, negative supply voltage which define the input potential for open inputs.

In this instance iC-MSB's reverse polarity protection feature can be activated as the outputs are tristate during the start phase and the resistances in the PLC determine the pin potential. During the start phase neither the supply VDD nor the output pins, which are also monitored, must fall to below ground potential (pin GND); otherwise the device is not configured and the outputs remain permanently set to tristate.

In order to ensure that iC-MSB starts with the PLCs mentioned above pull-up resistors can be used in the encoder. Values of $100 k\Omega$ are usually sufficient; it is, however, recommended that PLC specifications be specifically referred to here.



Rev D2, Page 28/29

iC-Haus expressly reserves the right to change its products and/or specifications. An Infoletter gives details as to any amendments and additions made to the relevant current specifications on our internet website www.ichaus.de/infoletter; this letter is generated automatically and shall be sent to registered users by email.

Copying - even as an excerpt - is only permitted with iC-Haus approval in writing and precise reference to source.

iC-Haus does not warrant the accuracy, completeness or timeliness of the specification on this site and does not assume liability for any errors or omissions in the materials. The data specified is intended solely for the purpose of product description. No representations or warranties, either express or implied, of merchantability, fitness for a particular purpose or of any other nature are made hereunder with respect to information/specification or the products to which information refers and no guarantee with respect to compliance to the intended use is given. In particular, this also applies to the stated possible applications or areas of applications of the product.

iC-Haus conveys no patent, copyright, mask work right or other trade mark right to this product. iC-Haus assumes no liability for any patent and/or other trade mark rights of a third party resulting from processing or handling of the product and/or any other use of the product.

As a general rule our developments, IPs, principle circuitry and range of Integrated Circuits are suitable and specifically designed for appropriate use in technical applications, such as in devices, systems and any kind of technical equipment, in so far as they do not infringe existing patent rights. In principle the range of use is limitless in a technical sense and refers to the products listed in the inventory of goods compiled for the 2008 and following export trade statistics issued annually by the Bureau of Statistics in Wiesbaden, for example, or to any product in the product catalogue published for the 2007 and following exhibitions in Hanover (Hannover-Messe).

We understand suitable application of our published designs to be state-of-the-art technology which can no longer be classed as inventive under the stipulations of patent law. Our explicit application notes are to be treated only as mere examples of the many possible and extremely advantageous uses our products can be put to.



Rev D2, Page 29/29

ORDERING INFORMATION

| Туре | Package | Order Designation |
|---|-------------------------------------|---------------------------------------|
| iC-MSB ^{SAFETY} | TSSOP20 TSSOP20 with thermal pad | iC-MSB TSSOP20 |
| Evaluation Board iC-MSB ^{SAFETY} | | iC-MSB EVAL MSB1D |
| iC-MSB2 Evaluation Board iC-MSB2 | TSSOP20 | iC-MSB2 TSSOP20 iC-MSB2 EVAL MSB1D |

For technical support, information about prices and terms of delivery please contact:

iC-Haus GmbH Am Kuemmerling 18 D-55294 Bodenheim GERMANY Tel.: +49 (61 35) 92 92-0 Fax: +49 (61 35) 92 92-192 Web: http://www.ichaus.com E-Mail: sales@ichaus.com

Appointed local distributors: http://www.ichaus.com/sales_partners